

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10/611,314	PEKAREK ET AL.
	Examiner	Art Unit
	Shambhavi Patel	2128
		Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Kim et al. 'Full Software Analysis and Impedance Matching of Radio Frequency CMOS Integrated Circuits'. Volume 23, March 2000. pages 183-189			
	V	Eo et al. "Generalized Coupled Interconnect Transfer Function and High-Speed Signal Simulations" IEEE Transactions of Microwave Theory and Techniques, Vol. 43 No. 5 May 1995.			
	W	Bockelman et al. "Combined Differential and Common-Mode Scattering Parameters: Theory and Simulation" IEEE Transactions on Microwave Theory and Techniques, Vol. 43 No. 7 July 1995.			
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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